

WHAT IS CLAIMED IS:

- 1                   1.       A composition comprising a liquid crystal dispersed within a polymer  
2 matrix, the polymer matrix formed by the cross-linking of a polyacrylate resin and a  
3 polyisocyanate resin, the liquid crystal exhibiting a minimum bulk resistivity of  $1 \times 10^{12}$   
4 ohm.cm and a voltage holding ratio (VHR) of 98% or greater.
- 1                   2.       The composition of claim 1 wherein the ratio of liquid crystal to  
2 polymer is between about 50/50 and 70/30 (wt/wt).
- 1                   3.       The composition of claim 1 exhibiting a driving voltage of 280 V or  
2 less across an air gap of at least 15  $\mu\text{m}$ .
- 1                   4.       The composition of claim 1 wherein the polyacrylate resin contains  
2 hydroxyl groups which can be used for cross-linking.
- 1                   5.       The composition of claim 1 wherein the liquid crystal is selected from  
2 the TL series available from EM Industries.
- 1                   6.       A method of detecting defective operation of an electro-optical device,  
2 the method comprising:  
3                   disposing a polymer dispersed liquid crystal (PDLC) overlying and separated  
4 from an underlying electro-optical device by an air gap, the PDLC having a polymer matrix  
5 formed by the cross-linking of a polyacrylate resin and a polyisocyanate resin, and having a  
6 liquid crystal exhibiting a minimum bulk resistivity of  $1 \times 10^{12}$  ohm.cm and a voltage holding  
7 ratio (VHR) of 98% or greater;  
8                   applying a voltage to a transparent electrode overlying the PDLC while  
9 illuminating the PDLC; and  
10                  detecting a changed intensity of light transmitted by the PDLC.
- 1                   7.       The method of claim 6 wherein the PDLC is disposed over a glass  
2 substrate bearing a thin film transistor.
- 1                   8.       The method of claim 6 wherein the changed intensity of light is  
2 detected by reflection of the incident light by a mirror.

1                   9.       The method of claim 6 wherein the PDLC comprises a ratio of liquid  
2 crystal to polymer of between about 50/50 and 70/30 (wt/wt).

1                   10.       The method of claim 6 wherein the applied voltage is between about  
2 100-320 V across an air gap of at least 5  $\mu\text{m}$ .

1                   11.       The method of claim 6 wherein the polyacrylate resin is selected from  
2 the group consisting of Paraloid AU1033 available from Rohm and Haas, and Doresco TA45-  
3 8 or Doresco TA65-1 available from Dock Resins.

1                   12.       The method of claim 6 wherein the polyisocyanate resin comprises an  
2 aliphatic polyisocyanate such as Desmodur N-75 from Bayer Polymers.

1                   13.       The method of claim 6 wherein the liquid crystal is selected from the  
2 TL series available from EM Industries.

1                   14.       An apparatus for inspecting a semiconductor device, the apparatus  
2 comprising:  
3                   a support for a semiconductor device;  
4                   an electro-optic modulator separated from the support by an air gap, the  
5 electro-optic modulator comprising,  
6                   a mirror disposed proximate to the support,  
7                   a transparent electrode distal from the support, and  
8                   a polymer dispersed liquid crystal (PDLC) sensor material disposed  
9 between the transparent electrode and the mirror, the PDLC having a polymer  
10 matrix formed by the cross-linking of a polyacrylate resin and a  
11 polyisocyanate resin, and a liquid crystal exhibiting a minimum bulk  
12 resistivity of  $1 \times 10^{12}$  ohm.cm and a voltage holding ratio (VHR) of 98% or  
13 greater;  
14                   a light source configured to illuminate the PDLC material during application  
15 of a voltage to the transparent electrode; and  
16                   a detector configured to detect intensity of light reflected by the mirror.

1                   15.       The apparatus of claim 14 wherein the support comprises a support for  
2 a workpiece bearing a thin film transistor.

1                   16.     The apparatus of claim 14 wherein the air gap has a width of between  
2     about 5-30  $\mu\text{m}$ , and a voltage of about 100-320 V is configured to be applied to the  
3     transparent electrode.

1                   17.     The apparatus of claim 14 wherein the liquid crystal is selected from  
2     the TL series available from EM Industries.